

Vishay Siliconix

N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$r_{DS(on)}\left(\Omega\right)$	I _D (A) ^{a, e}	Q _g (Typ)		
30	0.0029 at V _{GS} = 10 V	90	82 nC		
	0.0033 at V _{GS} = 4.5 V	90	02 IIC		

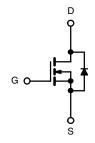
FEATURES

- TrenchFET® Power MOSFET
- 100 % R_g and UIS Tested



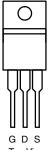
APPLICATIONS

- OR-ing
- Server
- DC/DC



N-Channel MOSFET

TO-220AB



DRAIN connected to TAB

Ordering Information: SUP90N03-03-E3 (Lead (Pb)-free)

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	30	V		
Gate-Source Voltage	V _{GS}	s ± 20			
	T _C = 25 °C		90 ^{a, e}		
Continuous Drain Current (T _{.I} = 175 °C)	T _C = 70 °C	1-	90 ^e	7	
Continuous Drain Current (1 _J = 175 °C)	T _A = 25 °C	I _D	28.8 ^{b, c}	A	
	T _A = 70 °C		27 ^{b, c}	^	
Pulsed Drain Current		I _{DM}	90		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	36		
Single Pulse Avalanche Energy	L = U. I IIII	E _{AS}	64.8	V	
Continuous Source-Drain Diode Current	T _C = 25 °C	I-	90 ^{a, e}	A	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	3.13 ^{b, c}		
	T _C = 25 °C		187 ^a		
Mayimum Payar Dissination	T _C = 70 °C	В	131	\Box w	
Maximum Power Dissipation	T _A = 25 °C	P _D	3.75 ^{b, c}	VV	
	T _A = 70 °C		2.63 ^{b, c}		
Operating Junction and Storage Temperature R	T _J , T _{stg}	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 sec	R _{thJA}	32	40	°C/W		
Maximum Junction-to-Case	Steady State	R _{th.IC}	0.5	0.6]		

Notes:

- a. Based on T_C = 25 °C. b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 sec.
- d. Maximum under Steady State conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 90 A.

SUP90N03-03

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SPECIFICATIONS T _J = 25 °C, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit	
Static				1	T	T	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		35		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	- '		- 7.5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.5		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	1	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μА	
	IDSS	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	90			Α	
Drain-Source On-State Resistance ^a	_	V _{GS} = 10 V, I _D = 28.8 A		0.0024	0.0029	Ω	
	r _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 27 \text{ A}$		0.0027	0.0033		
Forward Transconductance ^a	g _{fs}	V _{DS} = 15 V, I _D = 28.8 A		160		S	
Dynamic ^b					<u>'</u>		
Input Capacitance	C _{iss}			12065		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1725			
Reverse Transfer Capacitance	C _{rss}			970			
T. 10 . 0		$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 28.8 \text{ A}$		171	257		
Total Gate Charge	$Q_g = Q_g $			81.5	123		
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 28.8 \text{ A}$		34			
Gate-Drain Charge	Q _{gd}			29			
Gate Resistance	R_{g}	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t _{d(on)}			18	27	ns ns	
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 0.625 \Omega$		11	17		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 24 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		70	105		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			55	83		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 0.67 \Omega$		180	270		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 22.5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_q = 1 \Omega$		55	83		
Fall Time	t _f	·		12	18		
Drain-Source Body Diode Characteristic	-			L			
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			90		
Pulse Diode Forward Current ^a	I _{SM}				90	A	
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	-		52	78	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			70.2	105	nC	
Reverse Recovery Fall Time	t _a	$I_F = 20 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s, T}_J = 25 ^{\circ}\text{C}$		27		1	
Reverse Recovery Rise Time	t _b	-		25		ns	

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

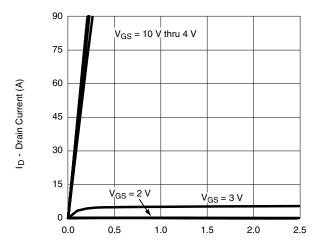
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



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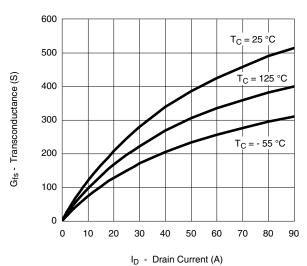
= - 55 °C

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

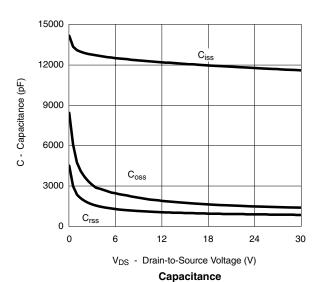


V_{DS} - Drain-to-Source Voltage (V)

Output Characteristics



Transconductance



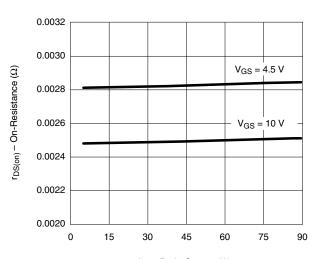
0.0

VGS - Gate-to-Source Voltage (V)

0

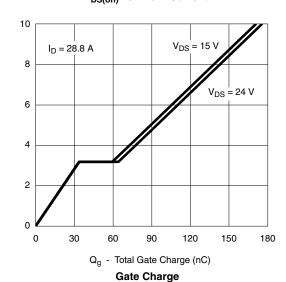
V_{GS} - Gate-to-Source Voltage (V)

Transfer Characteristics



I_D - Drain Current (A)

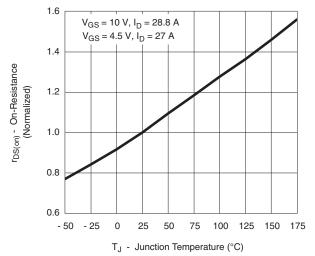
r_{DS(on)} vs. Drain Current



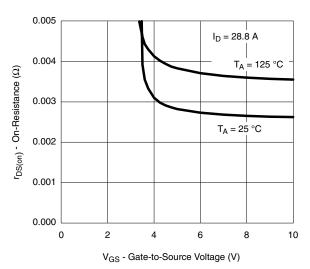
SUP90N03-03

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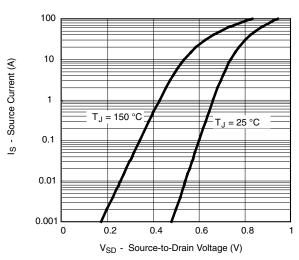
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



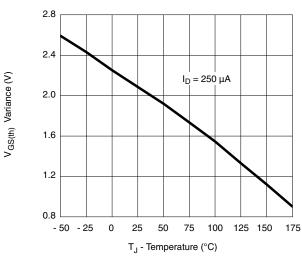
On-Resistance vs. Junction Temperature



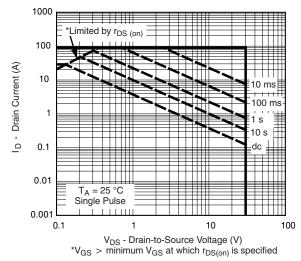
r_{DS(on)} vs. V_{GS} vs. Temperature



Forward Diode Voltage vs. Temperature



Threshold Voltage

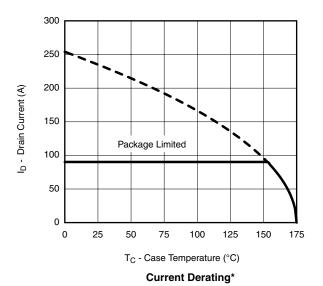


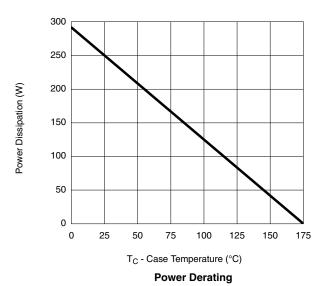
Safe Operating Area, Junction-to-Ambient



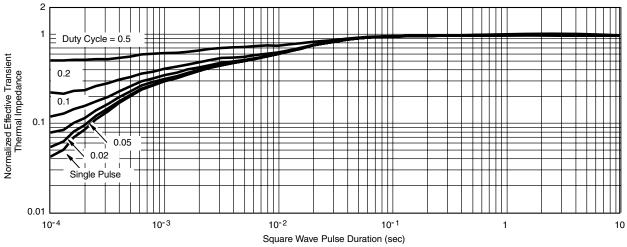
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





*The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see http://www.vishay.com/ppg?74341



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